



FEMTOCLOCKS™ CRYSTAL-TO-LVDS CLOCK GENERATOR

ICS844021I-01

GENERAL DESCRIPTION

The ICS844021I-01 is an Ethernet Clock Generator. The ICS844021I-01 uses an 18pF parallel resonant crystal over the range of 24.5MHz – 34MHz. For Ethernet applications, a 25MHz crystal is used. The ICS844021I-01 has excellent <1ps phase jitter performance, over the 1.875MHz – 20MHz integration range. The ICS844021I-01 is packaged in a small 8-pin TSSOP, making it ideal for use in systems with limited board space.

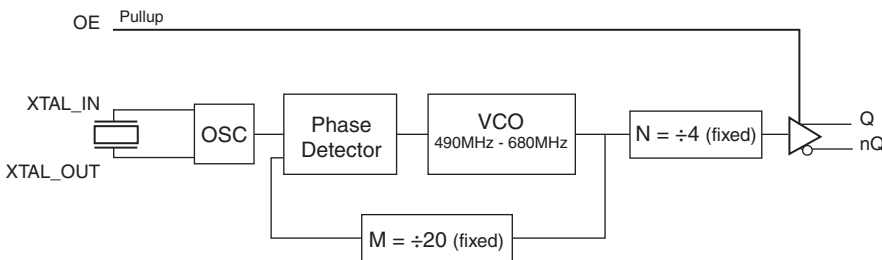
FEATURES

- One Differential LVDS output
- Crystal oscillator interface, 18pF parallel resonant crystal (24.5MHz – 34MHz)
- Output frequency range: 122.5MHz – 170MHz
- VCO range: 490MHz – 680MHz
- RMS phase jitter @ 125MHz, using a 25MHz crystal (1.875MHz – 20MHz): 0.32ps (typical) @ 3.3V
- 3.3V or 2.5V operating supply
- -40°C to 85°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

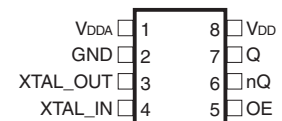
COMMON CONFIGURATION TABLE - Gb ETHERNET

Inputs				Output Frequency (MHz)
Crystal Frequency (MHz)	M	N	Multiplication Value M/N	
25	20	4	5	125
26.666	20	4	5	133.33
33.33	20	4	5	166.66

BLOCK DIAGRAM



PIN ASSIGNMENT



ICS844021I-01

8-Lead TSSOP

4.40mm x 3.0mm x 0.925mm

package body

G Package

Top View

TABLE 1. PIN DESCRIPTIONS

Number	Name	Type		Description
1	V _{DDA}	Power		Analog supply pin.
2	GND	Power		Power supply ground.
3, 4	XTAL_OUT, XTAL_IN	Input		Crystal oscillator interface. XTAL_IN is the input, XTAL_OUT is the output.
5	OE	Input	Pullup	Output enable pin. When HIGH, Q/nQ output is active. When LOW, the Q/nQ output is in a high impedance state. LVCMOS/LVTTL interface levels.
6, 7	nQ, Q	Output		Differential clock outputs. LVDS interface levels.
8	V _{DD}	Power		Core supply pin.

NOTE: *Pullup* refers to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ

ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5$ V
Outputs, I_O (LVDS)	
Continuous Current	10mA
Surge Current	15mA
Package Thermal Impedance, θ_{JA}	129.5°C/W (0 mps)
Storage Temperature, T_{STG}	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 3A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Core Supply Voltage		3.135	3.3	3.465	V
V_{DDA}	Analog Supply Voltage		$V_{DD} - 0.10$	3.3	V_{DD}	V
I_{DD}	Power Supply Current				75	mA
I_{DDA}	Analog Supply Current				10	mA

TABLE 3B. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Core Supply Voltage		2.375	2.5	2.625	V
V_{DDA}	Analog Supply Voltage		$V_{DD} - 0.10$	2.5	V_{DD}	V
I_{DD}	Power Supply Current				70	mA
I_{DDA}	Analog Supply Current				10	mA

TABLE 3C. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$ OR $2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	$V_{DD} = 3.3V$	2		$V_{DD} + 0.3$	V
		$V_{DD} = 2.5V$	1.7		$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	$V_{DD} = 3.3V$	-0.3		0.8	V
		$V_{DD} = 2.5V$	-0.3		0.7	V
I_{IH}	Input High Current	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$			5	μA
I_{IL}	Input Low Current	$V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-150			μA

TABLE 3D. LVDS DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage		275		425	mV
ΔV_{OD}	V_{OD} Magnitude Change				50	mV
V_{OS}	Offset Voltage		1.15		1.45	V
ΔV_{OS}	V_{OS} Magnitude Change				50	mV

NOTE: Please refer to Parameter Measurement Information for output information.

TABLE 3E. LVDS DC CHARACTERISTICS, $V_{DD} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage		215		430	mV
ΔV_{OD}	V_{OD} Magnitude Change				50	mV
V_{OS}	Offset Voltage		1.05		1.45	V
ΔV_{OS}	V_{OS} Magnitude Change				50	mV

NOTE: Please refer to Parameter Measurement Information for output information.

TABLE 4. CRYSTAL CHARACTERISTICS

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fundamental			
Frequency		24.5		34	MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF

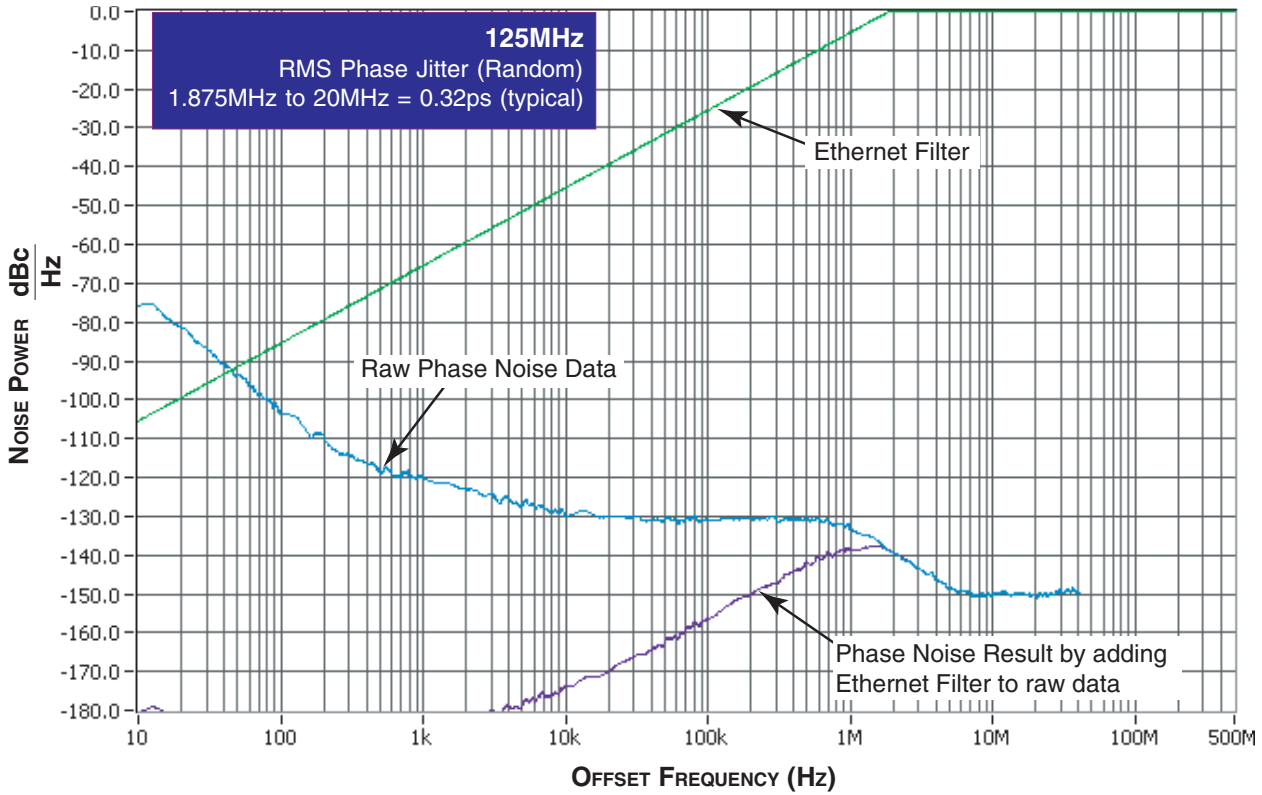
NOTE: It is not recommended to overdrive the crystal input with an external clock.

TABLE 5. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$ OR $2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

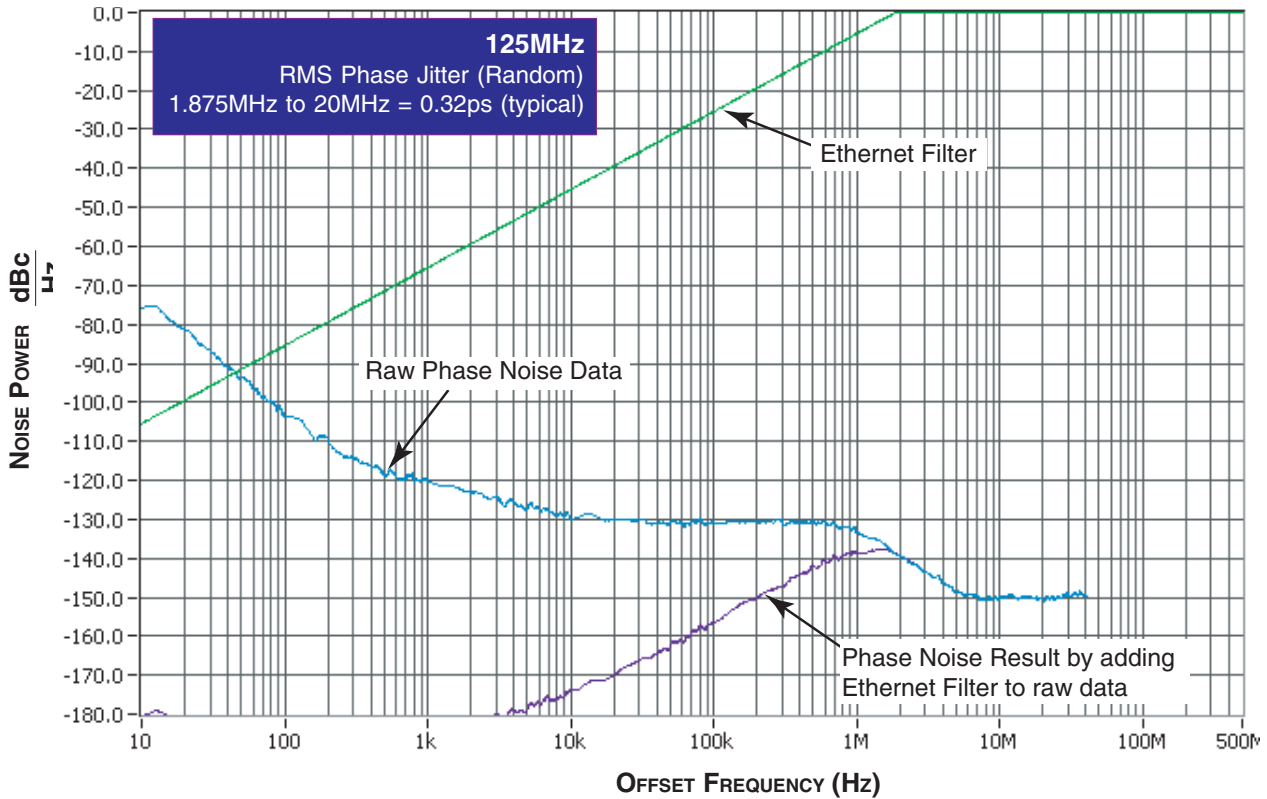
Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{OUT}	Output Frequency		122.5		170	MHz
$f_{jit}(\emptyset)$	RMS Phase Jitter (Random); NOTE 1	125MHz @ Integration Range: 1.875MHz - 20MHz		0.32		ps
t_R / t_F	Output Rise/Fall Time	20% to 80%	200		400	ps
odc	Output Duty Cycle		48		52	%

NOTE 1: Please refer to the Phase Noise Plots following this section.

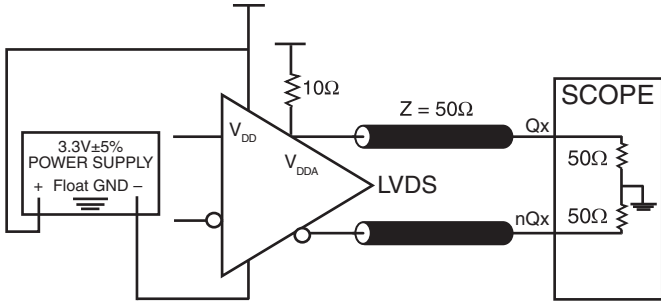
TYPICAL PHASE NOISE AT 125MHz @ 3.3V



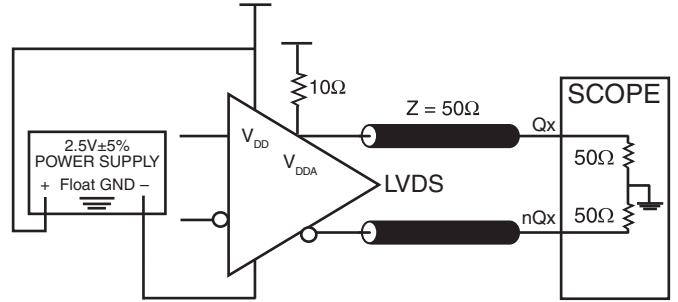
TYPICAL PHASE NOISE AT 125MHz @ 2.5V



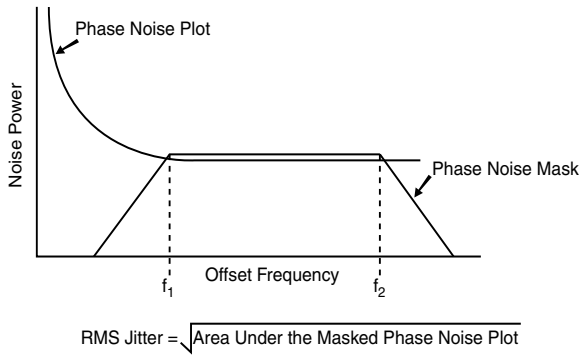
PARAMETER MEASUREMENT INFORMATION



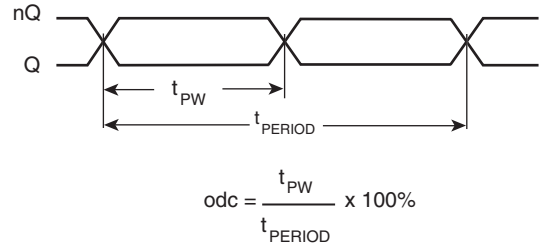
LVDS 3.3V OUTPUT LOAD AC TEST CIRCUIT



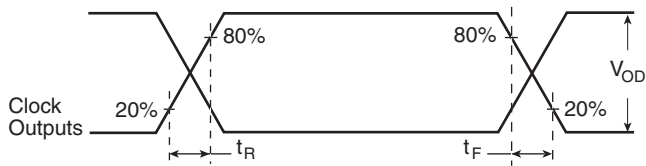
LVDS 2.5V OUTPUT LOAD AC TEST CIRCUIT



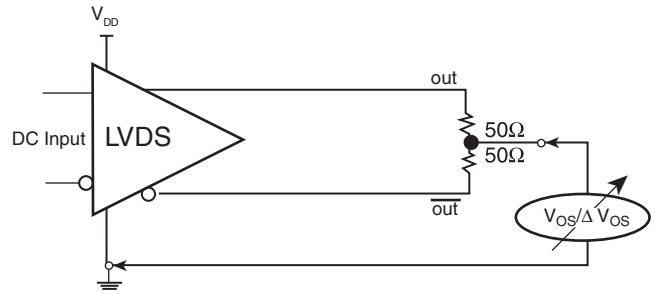
RMS PHASE JITTER



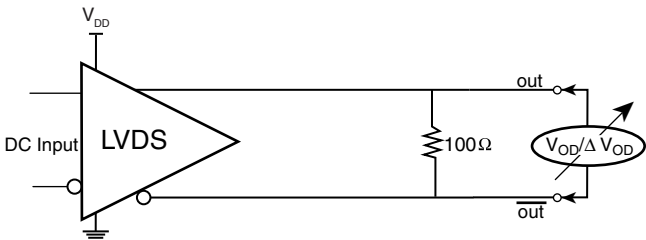
OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD



OUTPUT RISE/FALL TIME



OFFSET VOLTAGE SETUP



DIFFERENTIAL OUTPUT VOLTAGE SETUP

APPLICATION INFORMATION

POWER SUPPLY FILTERING TECHNIQUES

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. To achieve optimum jitter performance, power supply isolation is required. The ICS8440211-01 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. V_{DD} and V_{DDA} should be individually connected to the power supply plane through vias, and $0.01\mu\text{F}$ bypass capacitors should be used for each pin. *Figure 1* illustrates this for a generic V_{DD} pin and also shows that V_{DDA} requires that an additional 10Ω resistor along with a $10\mu\text{F}$ bypass capacitor be connected to the V_{DDA} pin.

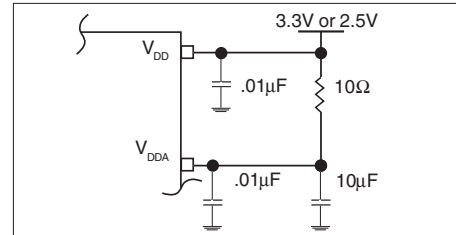


FIGURE 1. POWER SUPPLY FILTERING

CRYSTAL INPUT INTERFACE

The ICS8440211-01 has been characterized with 18pF parallel resonant crystals. The capacitor values, $C1$ and $C2$, shown in *Figure 2* below were determined using a 25MHz , 18pF parallel

resonant crystal and were chosen to minimize the ppm error. The optimum $C1$ and $C2$ values can be slightly adjusted for different board layouts.

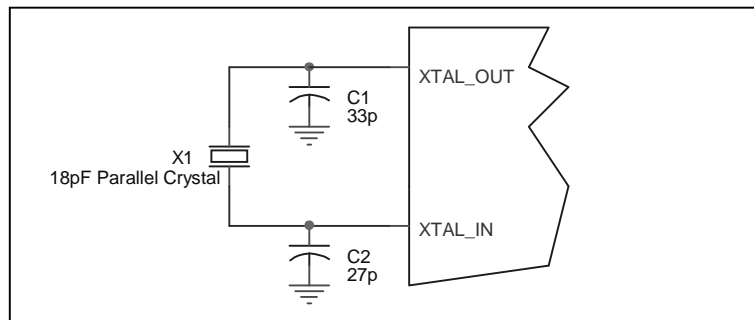


FIGURE 2. CRYSTAL INPUT INTERFACE

3.3V, 2.5V LVDS DRIVER TERMINATION

A general LVDS interface is shown in *Figure 4*. In a 100Ω differential transmission line environment, LVDS drivers require a matched load termination of 100Ω across near

the receiver input. For a multiple LVDS outputs buffer, if only partial outputs are used, it is recommended to terminate the unused outputs.

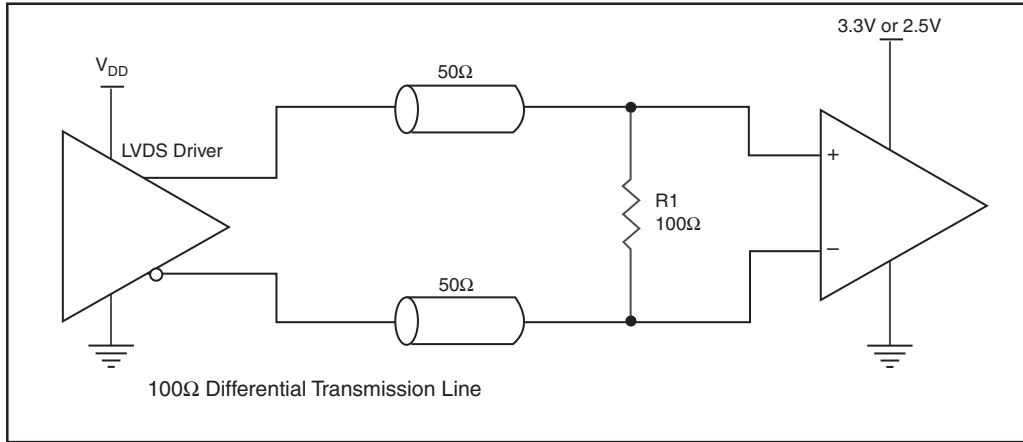


FIGURE 4. TYPICAL LVDS DRIVER TERMINATION

SCHEMATIC LAYOUT

Figure 5 shows an example of ICS844021I-01 application schematic. In this example, the device is operated at $V_{DD} = 3.3V$. The decoupling capacitor should be located as close as possible to the power pin. The 18pF parallel resonant 25MHz crystal is used. The C1 = 33pF and C2 = 27pF are recommended

for frequency accuracy. For different board layout, the C1 and C2 may be slightly adjusted for optimizing frequency accuracy. For the LVDS output drivers, place a 100Ω resistor as close to the receiver as possible.

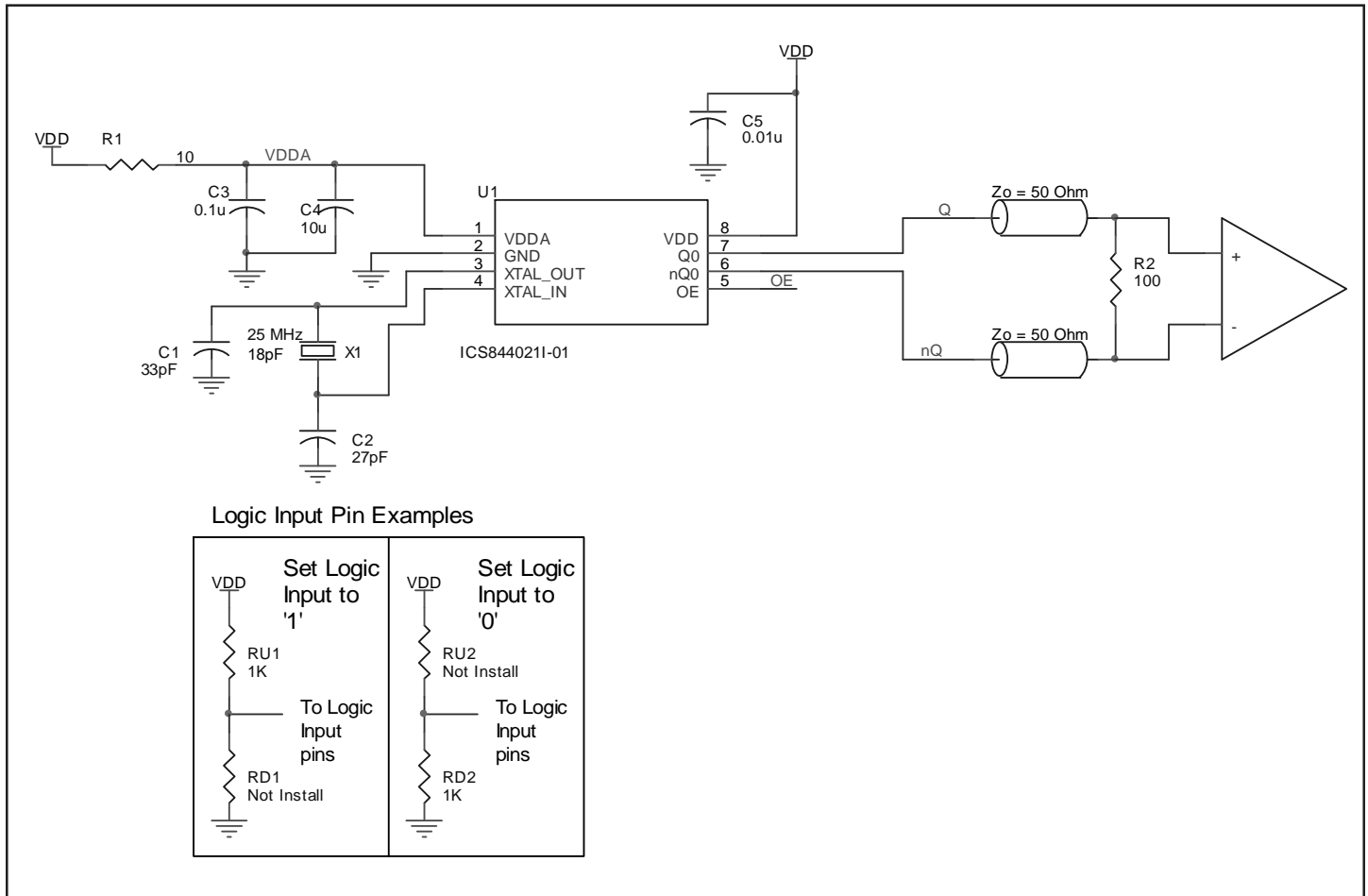


FIGURE 5. ICS844021I-01 SCHEMATIC LAYOUT

POWER CONSIDERATIONS

This section provides information on power dissipation and junction temperature for the ICS8440211-01. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS8440211-01 is the sum of the core power plus the analog plus the power dissipated in the load(s).

The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

- Power (core)_{MAX} = $V_{DD_MAX} * (I_{DD_MAX} + I_{DDA_MAX}) = 3.465V * (75mA + 10mA) = \mathbf{294.5mW}$

2. Junction Temperature.

Junction temperature, T_j, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature is 125°C.

The equation for T_j is as follows: $T_j = \theta_{JA} * Pd_total + T_A$

T_j = Junction Temperature

θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_{total} = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 129.5°C/W per Table 6 below.

Therefore, T_j for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.295\text{W} * 129.5^\circ\text{C}/\text{W} = 123.2^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example. T_j will obviously vary depending on the number of loaded outputs, supply voltage, air flow, and the type of board (single layer or multi-layer).

TABLE 6. THERMAL RESISTANCE θ_{JA} FOR 8-LEAD TSSOP, FORCED CONVECTION

θ_{JA} by Velocity (Meters per Second)			
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	129.5°C/W	125.5°C/W	123.5°C/W

RELIABILITY INFORMATION

TABLE 7. θ_{JA} VS. AIR FLOW TABLE FOR 8 LEAD TSSOP

θ_{JA} by Velocity (Meters per Second)			
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	129.5°C/W	125.5°C/W	123.5°C/W

TRANSISTOR COUNT

The transistor count for ICS844021I-01 is: 2533

PACKAGE OUTLINE & DIMENSIONS

PACKAGE OUTLINE - G SUFFIX FOR 8 LEAD TSSOP

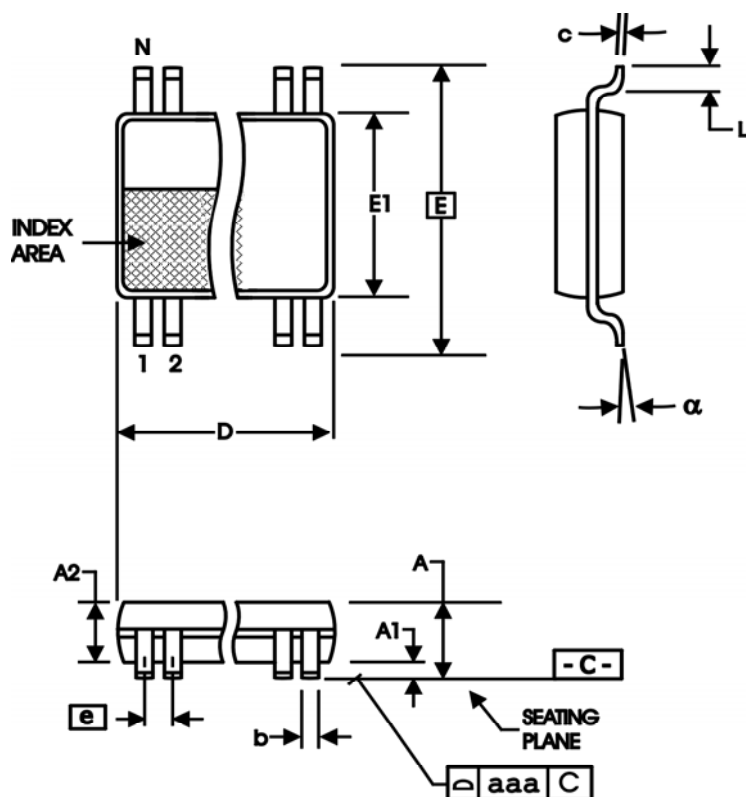


TABLE 8. PACKAGE DIMENSIONS

SYMBOL	Millimeters	
	Minimum	Maximum
N	8	
A	--	1.20
A1	0.05	0.15
A2	0.80	1.05
b	0.19	0.30
c	0.09	0.20
D	2.90	3.10
E	6.40 BASIC	
E1	4.30	4.50
e	0.65 BASIC	
L	0.45	0.75
α	0°	8°
aaa	--	0.10

Reference Document: JEDEC Publication 95, MO-153

TABLE 9. ORDERING INFORMATION

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
ICS844021BGI-01	2BI01	8 lead TSSOP	tube	-40°C to 85°C
ICS844021BGI-01T	2BI01	8 lead TSSOP	tape & reel	-40°C to 85°C
ICS844021BGI-01LF	BI01L	8 lead "Lead-Free" TSSOP	tube	-40°C to 85°C
ICS844021BGI-01LFT	BI01L	8 lead "Lead-Free" TSSOP	tape & reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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REVISION HISTORY SHEET

Rev	Table	Page	Description of Change	Date
A	T4	1	Deleted HiPerClockS references.	9/23/12
		4	Crystal Characteristics Table - added note.	
		8	Deleted application note, LVCMOS to XTAL Interface.	
		12	Deleted quantity from tape and reel.	

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